Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/690,542	ENDO, TAKEFUMI	
Examiner	Art Unit	
David Mis	2817	

	SEARCHED			
Class	Subclass	Date	Examiner	
331	1R, 14, 16, 17, 25, 36C, 117R,	6/13/2005	DM	
	117FE,			
	· 177R,		4	
	177V,			
	179			
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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